

FAST - (1059830.wsp.1)

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DB: US-PG-PUB US-PAT EPO JPO DERWENT BM TOB

Default operator: OR

Plots Highlight all hits initially

L2: (23263) (measur\$4 or test\$4 or calculat\$4)

L3: (225) 1 and 2

L4: (29) 3 and test adj structure

L5: (25) 4 and line

L6: (286) 2 and test adj structure

L7: (4849) 324/158.1.ccls.

L8: (130) 2 and 7

L9: (12) 8 and test adj structure

L10: (8982) 324/765,763,158.1,719.ccls.

L11: (365) 2 and 10

L12: (41) 11 and test adj structure

L13: (964) 714/733,734.ccls.

L15: (1) 14 and test adj structure

L14: (19) 2 and 13

L16: (7) Backward citation search 1

L17: (3) Backward citation search 2

L18: (2) Backward citation search 3

L19: (5) Backward citation search 4

L20: (10) Backward citation search 5

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	U	1	Document ID	Issue Dat	Pages	Title	Current OR	Current XR	Retrieval	Inventor	S	C	P	3	
1			US 6788074	20040907	14	System and method for using a capacitance mea	324/663	324/765;		Sarma; Robin C. et al.					
2			FR 2780162	19991224	14	Test structure for measurement of multilay		438/17;		FROMENT, B					
3			EP 1116957	20010718	6	Circuit for measuring capacitances of structu				LINDOLF, J et al.					
4			US 6366098	20020402	14	Test structure, integrated circuit, and	324/678	324/158.1;		Froment; Benoit					
5			US 6404222	20020611	11	Chip capacitance measurement circuit	324/765	324/537;		Fan; Chen-Teng et al.					
6			US 6501283	20021231	6	Circuit configuration for measuring the capac	324/679	324/519;		Lindolf; Jurgen et al.					
7			US 6700399	20040302	11	High density parasitic measurement structure	324/765	324/761;		Savithri; Nagaraj					
8			US 5999010	19991207	6	Method of measuring interconnect coupling c	324/765	438/18		Narasimh					
			A					324/658		Arora; Narain D. et al.					

Hits Details HTML

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